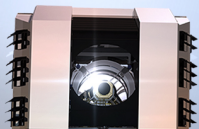


ISR: DM and Camera

Robert Lupton, Princeton University
LSST Pipeline/Calibration Scientist

2020-08-19



PST ISR



Introduction

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- DM: Andrés Plazas, Merlin Fisher-Levine, Chris Waters, . . .
- Camera: Jim Chiang, Aaron Roodman, Seth Digel, Adam Snyder, Yousuke Utsumi, . . .
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E.g. in writing this talk I used Andrés's page

<https://confluence.lsstcorp.org/display/DM/Sensor+Characterization+and+ISR> which is informed by discussions at the SAWG and Camera Verification meetings



Flux levels

$$N_{\text{photon}} = \frac{15.09}{R} \left(\frac{S_{\nu}}{\mu\text{Jy}} \right) \left(\frac{t}{s} \right) \left(\frac{A}{m^2} \right)$$

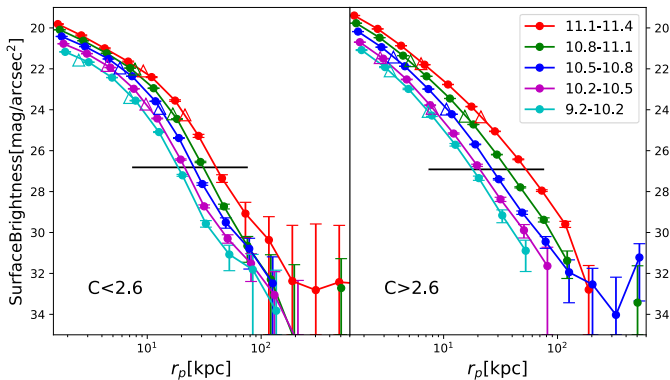
In a 30s Rubin exposure, a $1\mu\text{Jy}$ source produces c. 3000 counts; 1 ADU/pixel is c. 29.1 AB asec^{-2} .



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HSC *r*
Wang *et al.* 2019
arXiv:1811.04714



- saturation and suspect pixel masking
- overscan subtraction
- CCD assembly of individual amplifiers
- bias subtraction
- variance image construction
- linearization of nonlinear response
- crosstalk correction
- mask defects, edges, nans, etc.
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Bias and Overscan

DM subtracts an overscan-corrected 2-D master bias with mean ~ 0 , and an offset estimated from the overscan.



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 - Stay tuned!





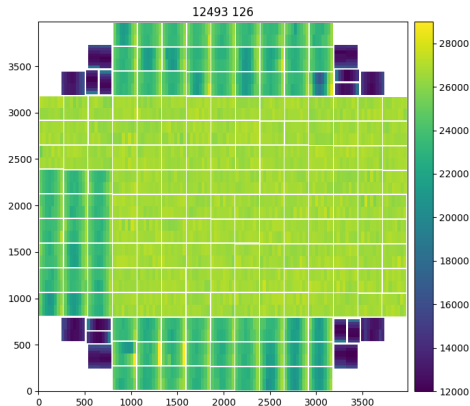
Bias levels

The lsstCam has high bias levels, c. 22000 – 27000 ADU



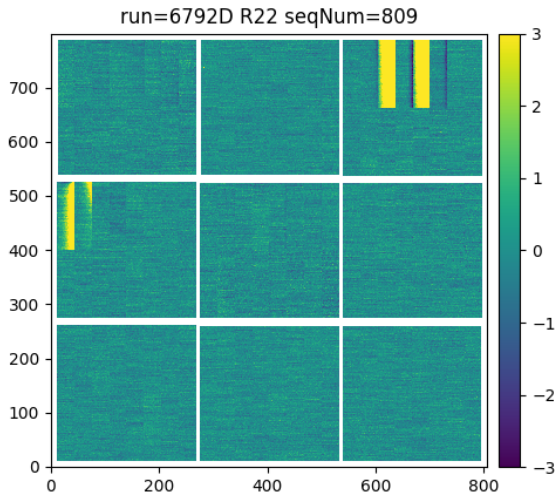
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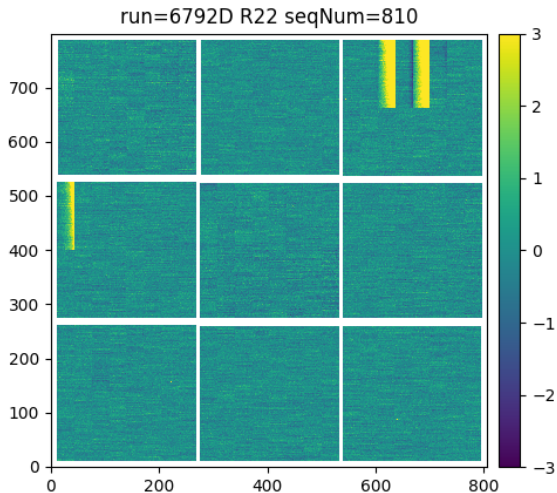




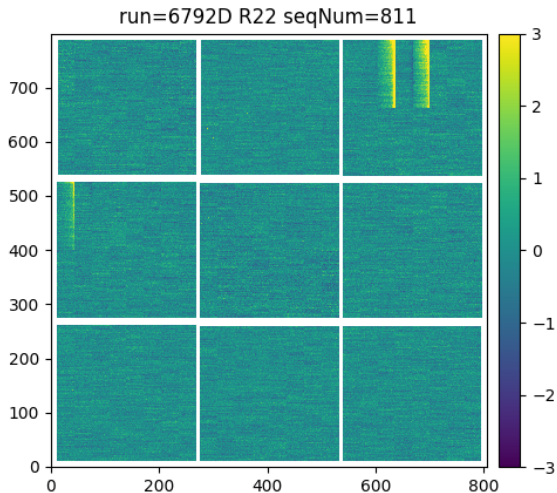
Run 6792D, Raft R22 (bias, oscan per-row)



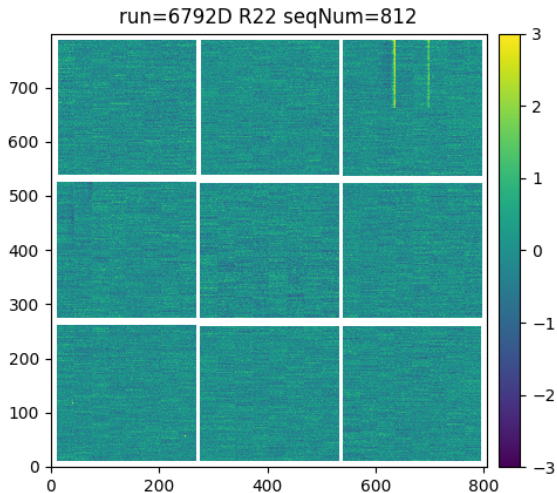
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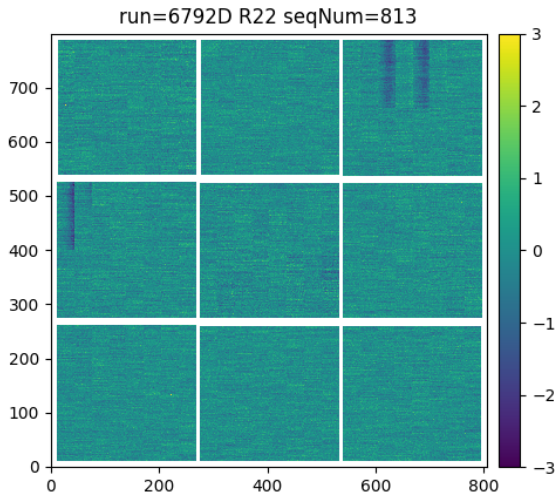


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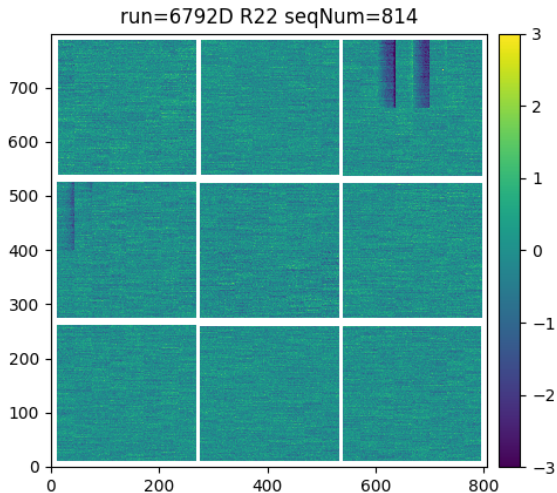




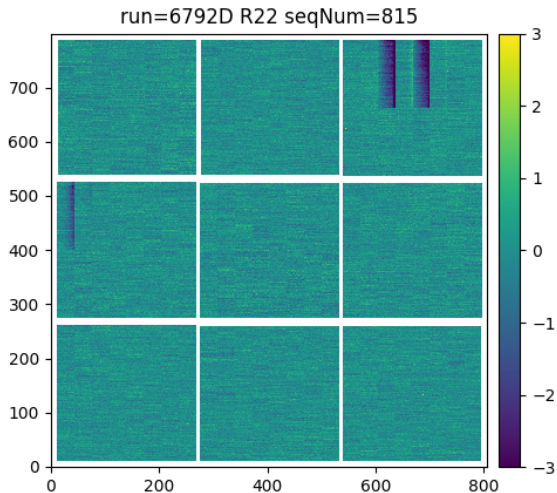
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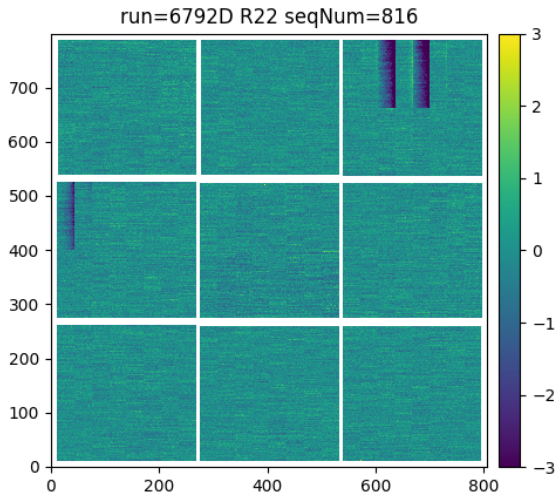


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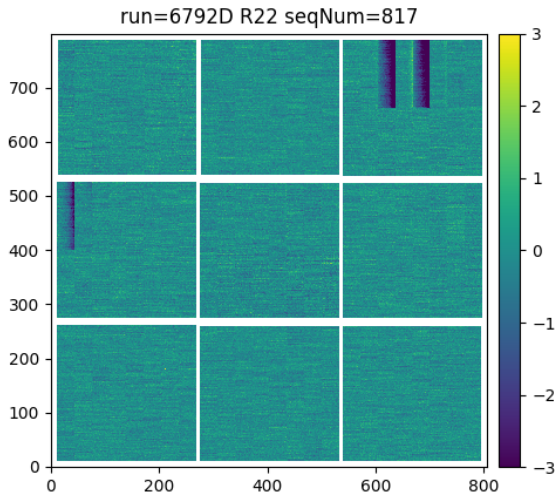


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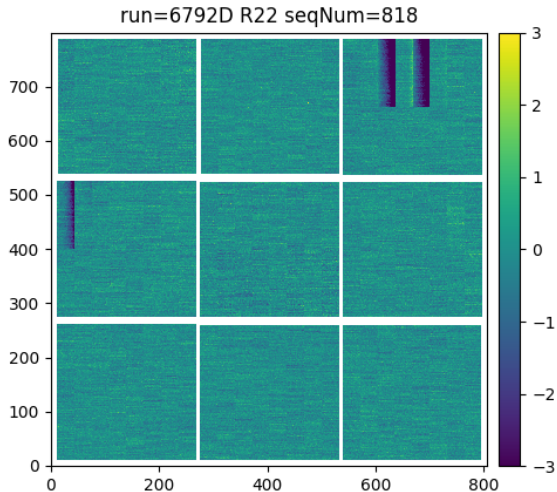




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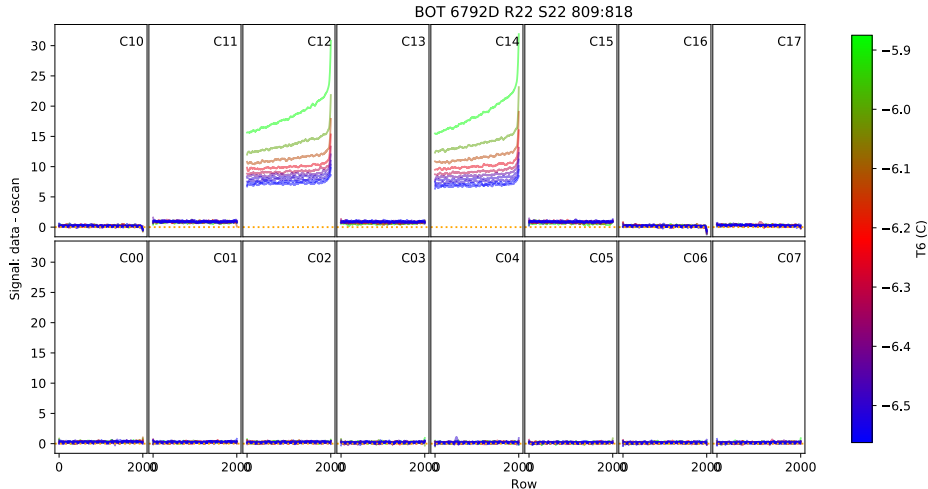


BOT R22 S22 C12 seqNum: 809–818

What's going on with R22 S22 (E2V-CCD250-360)?

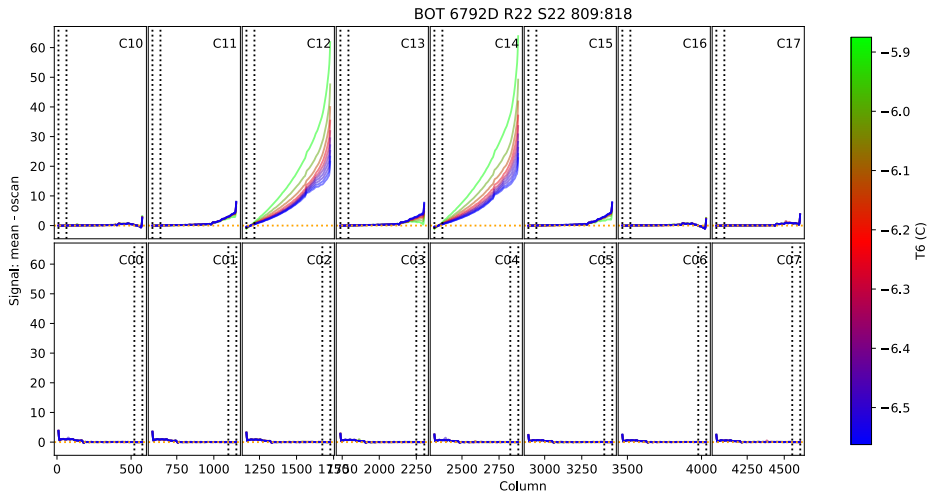


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Gain variation

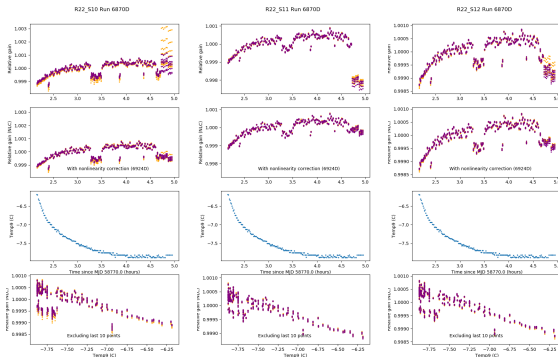
1. Gain: drift over time and temperature



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- And a jump due to the back-bias voltage (VBB) changing; problem in power supplies

2. Changes in (Non-)Linearity? Probably small?



Seth Digel

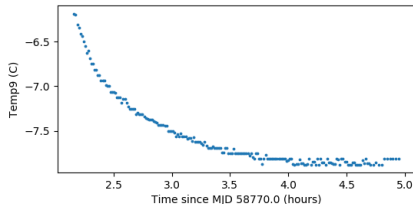
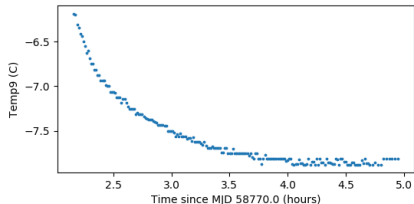
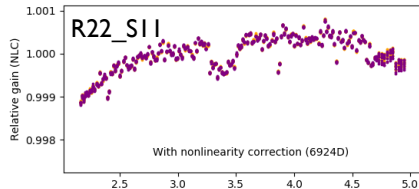
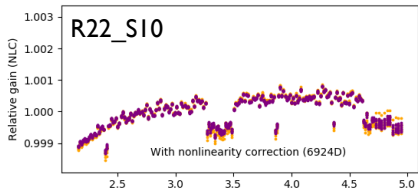




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Relative gain drifts between CCDs and (worse) amplifiers is a problem for sky subtraction.



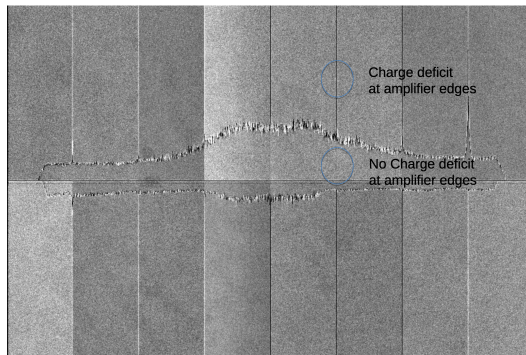
Tearing and Persistence in E2V CCDs

1. Tearing: "classic"
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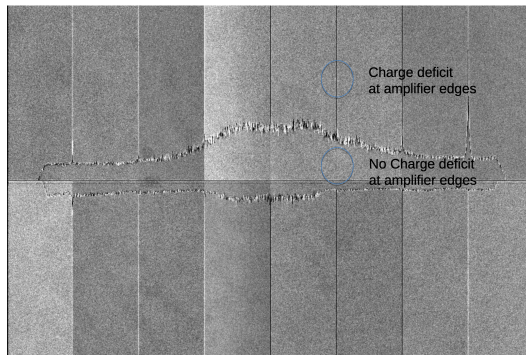
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Pierre Antilogus, Claire Juramy, "Running e2v sensor in bipolar", 2019-07-14



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Tearing is **solved** by inverting voltages; investigating divisadero



Unwanted Signal

1. Dark current
2. Localized glows
 - Serials
 - Bulk

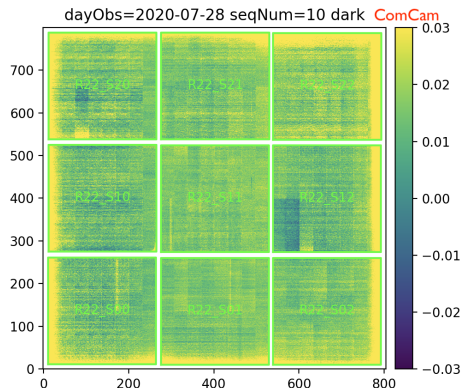


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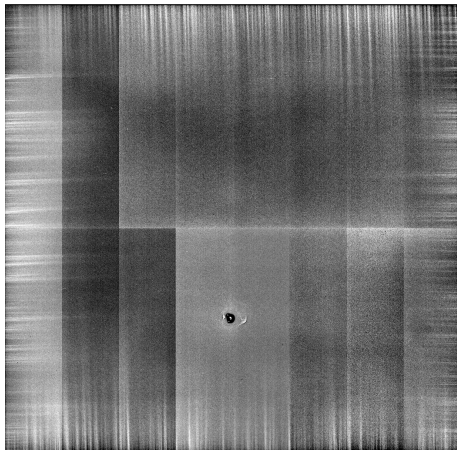
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Probably OK if stable



"Combs"

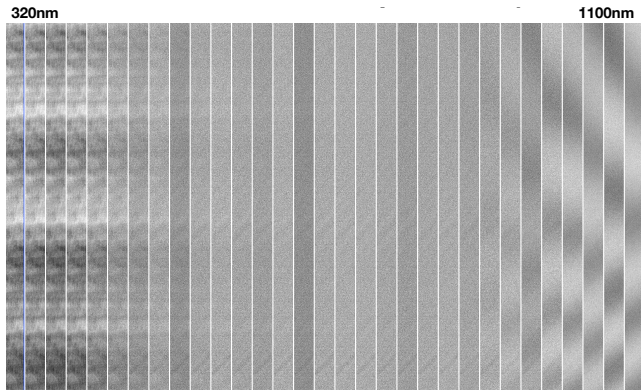
1. Comb-like pattern in the far red ($\lambda > 1\mu m$)



1.05 μm Yousuke Utsumi, 2019-8-13



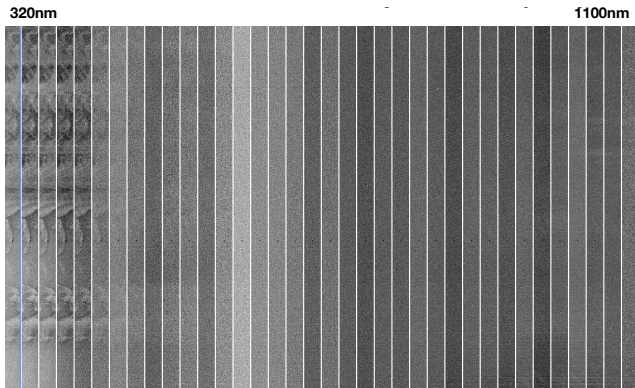
1. Flat fields
2. "Annealing" (E2V), "Coffee stains" (ITL)
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Yousuke Utsumi, 2019-8-13



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ITL

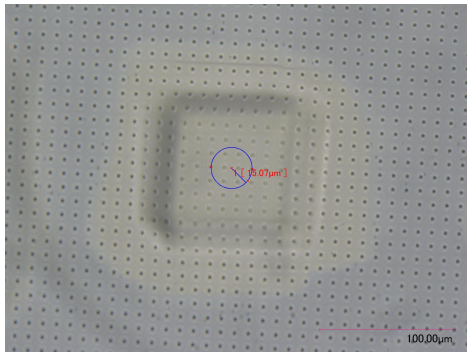
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1. Bad pixels
2. Midline "bloom stop" for E2V
3. Tree rings
4. Edge distortions
5. Pixel size variation



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E2V B dots
Craig Lage
arXiv:1911.09577v1.



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DM:

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- Think about small-scale effects
- Worry about whether these effects are really static



1. Serial CTE (and serial traps)

- Fails specifications (req: $CTE = 5e-6$ from EPER) for a significant fraction of the ITL amps

2. Parallel CTE

- Seems OK (req: $CTE = 3e-6$ from EPER)





Charge Transfer [In]Efficiency

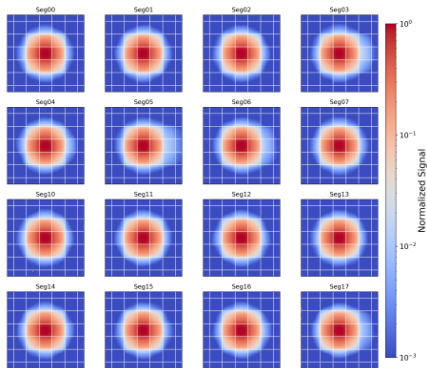
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Snyder and Roodman 2020
arXiv:2001.03223



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Because the readnoise is added *after* the CTE effect, correcting for CTE leads to correlated noise.



Bleeding/Blooming

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- Not measured for resolved sources during EOTesting, not clear if PTC measures the same thing

Interpolated/masked along with defects



Brighter-Fatter

1. Brighter-fatter



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Current algorithms correct c. 90% of the effect



1. Voltage Testing And Optimization
2. Excessive power dissipation
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1. Voltage Testing And Optimization
2. Excessive power dissipation
3. Cross talk (correction matrix)
 - Non-linearity is under study. Steve R.
4. ADC issues
5. Jitter and jitter cleaner
6. Analog overshoot in the signal chain, incomplete reset



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DM's working on this with the camera team.



The End

